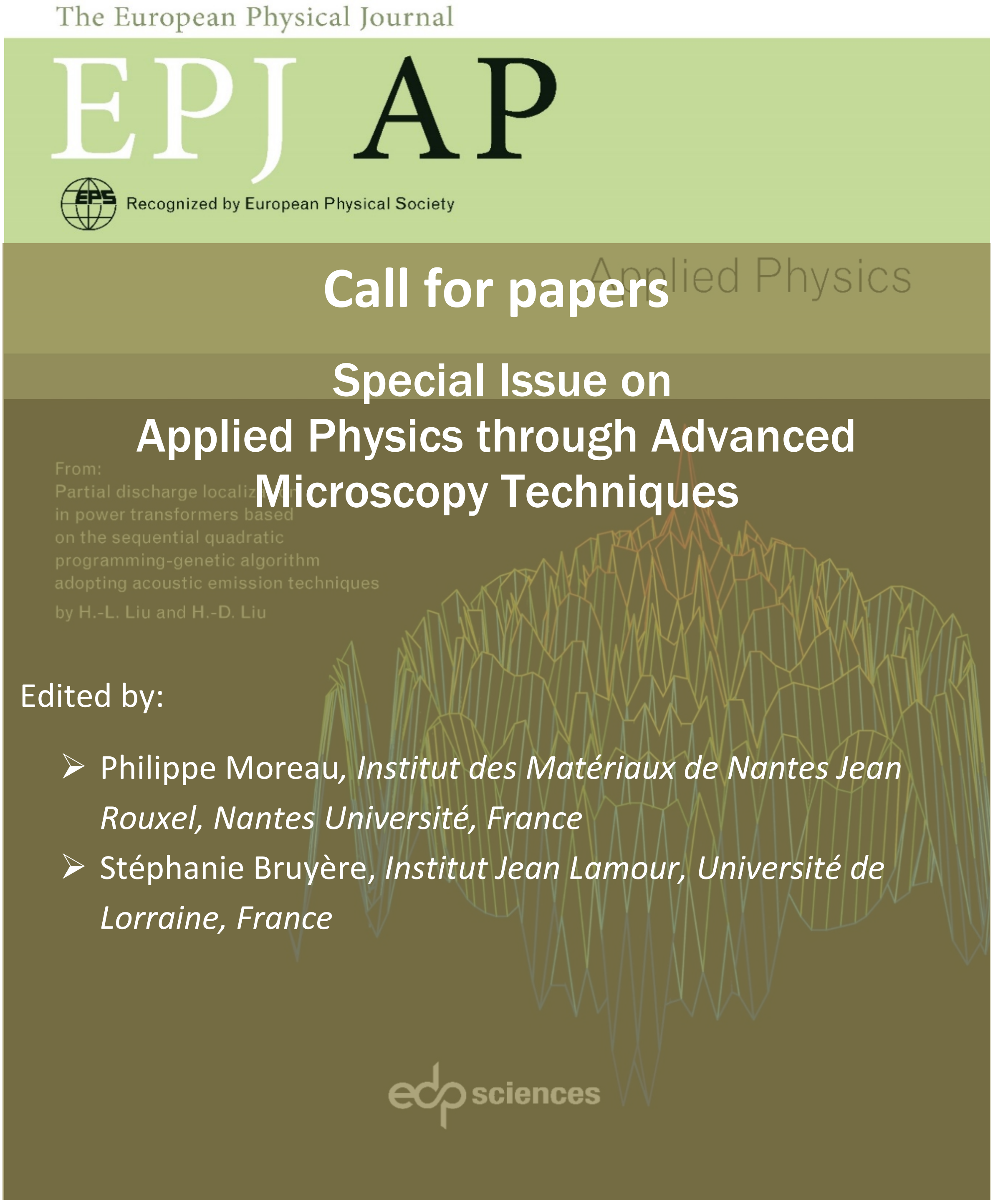

The European Physical Journal
EPJ AP
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Applied Physics

Call for papers

Special Issue on Applied Physics through Advanced Microscopy Techniques

From:
Partial discharge localiz
in power transformers based
on the sequential quadratic
programming-genetic algorithm
adopting acoustic emission techniques
by H.-L. Liu and H.-D. Liu

Edited by:

- Philippe Moreau, *Institut des Matériaux de Nantes Jean Rouxel, Nantes Université, France*
- Stéphanie Bruyère, *Institut Jean Lamour, Université de Lorraine, France*

edp sciences

Background

Microscopy techniques are both essential to advancement of applied physics in many domains and dependent on fundamental knowledge of physics phenomena. They are thus of significant importance in the quest for understanding and exploring materials, interfaces and complex objects of tomorrow.

Multidisciplinary approaches and interactions have become more and more evident as essential to the fast advancement of this research field. Gathering such diverse researchers can only generate very innovative ideas and applications, be it through physical meetings or associating papers in a theme issue.

Aim and Scope of the Themed Issue

The aim of this Special Issue on Applied Physics through Advanced Microscopy Techniques is to assemble high-quality papers that include the recent progress and current research within the development and application of microscopy using photons, electrons and/or scanning probe techniques. Contributions putting forward multidisciplinary approaches are most welcome.

The Scope of papers that will be considered for publication in this Special Issue covers:

- **(i)** Interfaces in Materials Science
- **(ii)** Physical Tools for Biological Imaging: From Molecules to Organisms
- **(iii)** Quantitative Property Measurement Using Electron Beams
- **(iv)** Time-Resolved Techniques
- **(v)** Emerging Methods for Microscopy Data Processing
- (vi) Advances in Instrumentation
- (vii) New Frontiers in Scanning Probe Microscopy;

This themed issue is published in connection with the 19th congress organized by the Société Française des Microscopies, held in Toulouse, July 1st –July 4th, 2025.

Submissions

All relevant papers will be carefully considered, reviewed by a distinguished team of international experts, and published in accordance to the Journal's standard policies. Full research papers and comprehensive review articles can be submitted online via the journal's submission and peer review site. The authors wishing to use the template of the journal can find it here.

Submission deadline – October 31st 2025

Charges

1. There is no submission charge in EPJAP.
2. For papers that have not chosen the Open Access Option (those papers will be read only by subscribers), there are **no publication charges.**

3. Open Access Option

To favour a broad and easy access to all published scientific information, EPJ AP uses a service called Open Access Option (OAO). It offers the possibility for authors to make their papers freely available to all interested readers (subscribers or non subscribers) as soon as the articles are published online, in exchange for payment of a basic fee.

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